

**Notice of References Cited**

Application/Control No.

09/989,390

Applicant(s)/Patent Under  
Reexamination  
OHKI, MASAHIKO

Examiner

Mark Eashoo, Ph.D.

Art Unit

1732

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,486,195	12-1969	Greenwood et al.	425/131.1
	B	US-5,221,541	06-1993	Arbour et al.	425/188
	C	US-5,527,499	06-1996	Miley, Gary D.	264/40.1
	D	US-6,294,119	09-2001	Nakamura, Yoshinori	264/173.12
	E	US-6,478,564	11-2002	Tieu et al.	425/145
	F	US-6,491,510	12-2002	Tieu et al.	425/145
	G	US-2002/0086082	07-2002	Grossi, Victor M.	425/467
	H	US-2002/0190417	12-2002	Helle et al.	264/104
	I	US-3,584,343	06-1971	Kohlepp et al.	425/130
	J	US-3,609,806	10-1971	Schippers et al.	425/197
	K	US-3,830,610	08-1974	Ohkawa et al.	425/141
	L	US-3,850,568	11-1974	Bartha et al.	425/466
	M	US-4,088,433	05-1978	Simpson, Howard D.	425/464

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a) )  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.